	Application No.	Applicant(s)
AL C. PAUL LING	10/663,663	SHIMA ET AL.
Notice of Allowability	Examiner	Art Unit
	Stephen Yam	2878
The MAILING DATE of this communication appearance All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIOF the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this apport or other appropriate communication IGHTS. This application is subject to	plication. If not included will be mailed in due course. THIS
1. $igspace$ This communication is responsive to <u>amendment filed Dec</u>	<u>ember 27, 2005</u> .	
2. ⊠ The allowed claim(s) is/are <u>1-18</u> .		
3. Acknowledgment is made of a claim for foreign priority una a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 4. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give 5. CORRECTED DRAWINGS (as "replacement sheets") must (a) including changes required by the Notice of Draftspers 1) hereto or 2) to Paper No./Mail Date	e been received. e been received in Application No cuments have been received in this of this communication to file a reply MENT of this application. sitted. Note the attached EXAMINER es reason(s) why the oath or declarate to be submitted. Son's Patent Drawing Review (PTO-	national stage application from the complying with the requirements 'S AMENDMENT or NOTICE OF ation is deficient.
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t		
 DEPOSIT OF and/or INFORMATION about the depo attached Examiner's comment regarding REQUIREMENT 		
Attachment(s) 1. ☐ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. Interview Summary Paper No./Mail Da 7. Examiner's Amenda	te
	F	THANH X. LUU PRIMARY EXAMINER

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REASONS FOR ALLOWANCE

1. Claims 1-18 are allowed over the prior art of record.

2. The following is an examiner's statement of reasons for allowance:

Regarding Claim 1, the invention as claimed, specifically in combination with a first conductivity first non-single crystalline semiconductor layer, a second conductivity second non-single crystalline semiconductor layer, a substantially intrinsic third non-single crystalline semiconductor layer between the first and second semiconductor layers, wherein many of crystal grains contained in the third semiconductor layer have major axes substantially perpendicular to said main surface of the substrate on an interfacial portion between the third semiconductor layer and the first and/or second semiconductor layer, with many of crystal grains contained in either the first or second semiconductor layer having major axes substantially parallel to the main surface of the substrate on the interfacial portion, is not disclosed or made obvious by the prior art of record.

Regarding Claim 9, the invention as claimed, specifically in combination with a first conductivity first non-single crystalline semiconductor layer, a second conductivity second non-single crystalline semiconductor layer, a substantially intrinsic third non-single crystalline semiconductor layer between the first and second layers, with the first and/or second semiconductor layers having a structure formed by stacking a first layer and a second layer with many of crystal grains in the first layer having major axes substantially parallel to the main surface of the substrate and many of crystal grains in the second layer having major axes

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substantially perpendicular to the main surface of the substrate, is not disclosed or made obvious by the prior art of record.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Stephen Yam whose telephone number is (571)272-2449. The examiner can normally be reached on Monday-Friday 8:30am-5pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Georgia Epps can be reached on (571)272-2328. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

SY

THANH X. LOU DRIMARY EXAMINER